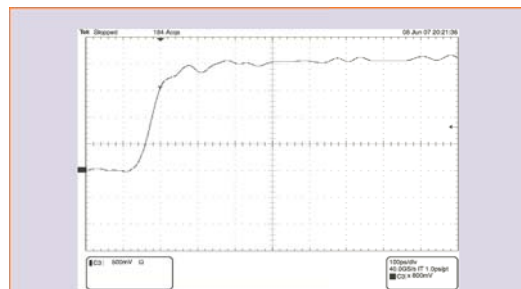


# Immunity Tester

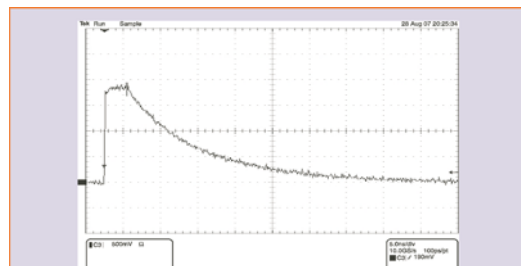


LSI Immunity Tester

model HIT-5000



0.1Ω probe waveform, 0.5V 100pS/div



Tf module waveform, 0.5V 5nS/div

## Features

- Using TLP Technology
- Realization of zapping by Low low impedance (0.1Ω)
- Pulse waveform change (Tw, Tr/Tf)
- Tf changed independently
- Single/serial zapping
- Possibly select bipolar of zapping

## Specification

Zap Voltage	0~4kV
Polarity	+ / -
Interval time	10mS~1S / Step 10mS
Zap mode	setting / serial
Pulse width	1n, 10n, 100nS
Rise time (No filter)	less than 100pS (0~2 kV) less than 500pS (2~4kV)
Probe (optional)	1Ω / 0.1Ω (0.2Ω)
Filter (optional)	1n, 5n, 10n, 20nS fixtures
Tf module	10nS

As devices grow more crowded, Vdd/Vcc of LSI is showing a tendency to fall. With it The immunity has the same tendency and it's regarded as important as a test item. As usual when impress a pulse by ESD guns, in the positive polarity is applied to the pin LSI appear supply voltage to the noise and vibration waveform may be. In particular, the positive and the negative direction of Malfunctions threshold be different, and the positive polarity applied, even though threshold negative direction surpassed by malfunctions that may occur. HIT-5000, the rectangle wave to put it in the direction of positive and negative both can be evaluated individually.

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